

Technical Data

Integrated Quad Half H-Bridge with Power Supply, Embedded MCU, and LIN Serial Communication

Thermal Addendum

Introduction

This thermal addendum ia provided as a supplement to the MM908E625 technical data sheet. The addendum provides thermal performance information that may be critical in the design and development of system applications. All electrical, application and packaging information is provided in the data sheet.

Package and Thermal Considerations

This MM908E625 is a dual die package. There are two heat sources in the package independently heating with P_1 and P_2 . This results in two junction temperatures, $T_{.11}$ and $T_{.12}$, and a thermal resistance matrix with $R_{0.IAmn}$.

For m, n = 1, $R_{\theta JA11}$ is the thermal resistance from Junction 1 to the reference temperature while only heat source 1 is heating with P_1 .

For m = 1, n = 2, $R_{\theta JA12}$ is the thermal resistance from Junction 1 to the reference temperature while heat source 2 is heating with P_2 . This applies to $R_{\theta J21}$ and $R_{\theta J22}$, respectively.

7 2	$egin{bmatrix} {\sf R}_{ heta JA11} \ {\sf R}_{ heta JA21} \end{split}$	$R_{ extsf{ heta}JA12} \ R_{ extsf{ heta}JA22}$		P ₁ P ₂	Ì
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The stated values are solely for a thermal performance comparison of one package to another in a standardized environment. This methodology is not meant to and will not predict the performance of a package in an application-specific environment. Stated values were obtained by measurement and simulation according to the standards listed below.

Standards

Thermal	1 = Power Chip, 2 = Logic Chip [°C/W]			
Resistance	m = 1, n = 1	m = 1, n = 2 m = 2, n = 1	m = 2, n = 2	
R _{0JAmn} ⁽¹⁾⁽²⁾	23	20	24	
R _{0JBmn} ⁽²⁾⁽³⁾	9.0	6.0	10	
R _{0JAmn} ⁽¹⁾⁽⁴⁾	52	47	52	
R _{θJCmn} ⁽⁵⁾	1.0	0	2.0	

Table 1. Thermal Performance Comparison

Notes:

 Per JEDEC JESD51-2 at natural convection, still air condition.

- 2. 2s2p thermal test board per JEDEC JESD51-7and JESD51-5.
- 3. Per JEDEC JESD51-8, with the board temperature on the center trace near the power outputs.
- 4. Single layer thermal test board per JEDEC JESD51-3 and JESD51-5.
- 5. Thermal resistance between the die junction and the exposed pad, "infinite" heat sink attached to exposed pad.

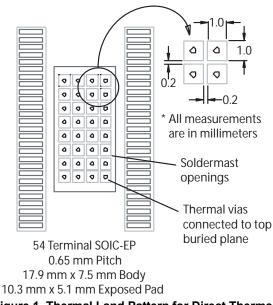
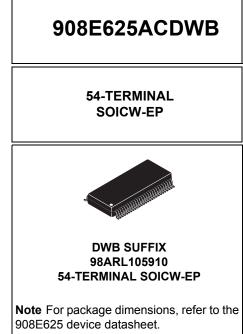


Figure 1. Thermal Land Pattern for Direct Thermal Attachment Per JEDEC JESD51-5





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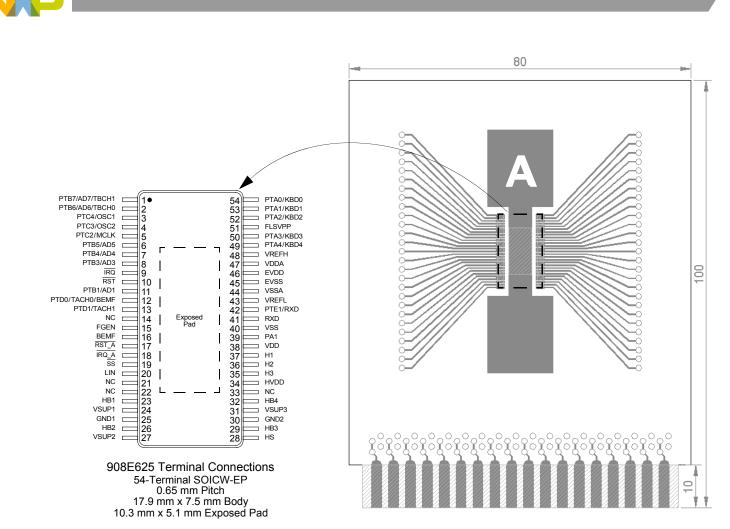


Figure 2. Thermal Test Board

Device on Thermal Test Board

Material:	Single layer printed circuit board FR4, 1.6 mm thickness Cu traces, 0.07 mm thickness
Outline:	80 mm x 100 mm board area, including edge connector for thermal testing
Area A :	Cu heat-spreading areas on board surface
Ambient Conditions:	Natural convection, still air

Table 2. Thermal Resistance Performance

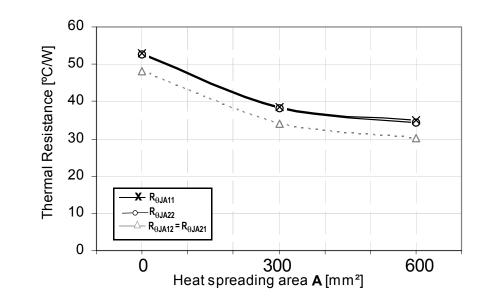
Thermal Resistance	Area A (mm ²)	1 = Power Chip, 2 = Logic Chip (°C/W)			
		m = 1, n = 1	<i>m</i> = 1, <i>n</i> = 2 <i>m</i> = 2, <i>n</i> = 1	m = 2, n = 2	
R _{θJAmn}	0	53	48	53	
	300	39	34	38	
	600	35	30	34	
R _{θJSmn}	0	21	16	20	
	300	15	11	15	
	600	14	9.0	13	

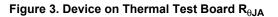
 $\mathsf{R}_{\theta JA}$ is the thermal resistance between die junction and ambient air.

 $R_{\theta JSmn}$ is the thermal resistance between die junction and the reference location on the board surface near a center lead of the package (see Figure 2)

This device is a dual die package. Index *m* indicates the die that is heated. Index *n* refers to the number of the die where the junction temperature is sensed.

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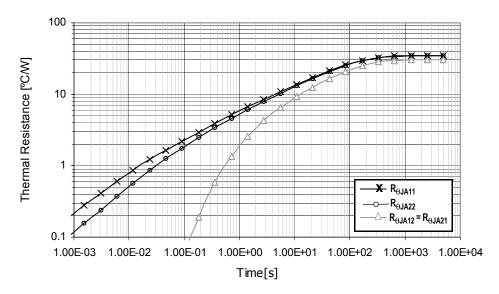


Figure 4. Transient Thermal Resistance $R_{\theta JA}$ (1.0 W Step Response) Device on Thermal Test Board Area A = 600 (mm²)



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